

Application/Control No.	Applicant(s)/Patent under Reexamination KANG ET AL.	
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Examiner	Art Unit	
Thuy V. Tran	2821	

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SEARCHED					
Class	Subclass	Date	Examiner		
*	Updated Search	4/12/2005	T.T.		
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		

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